

VDS	RDS(on)	ID@25℃
1200V	140mΩ	17A

**Applications:**

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC Converters
- EV Charging
- Motor Drives

**Features:**

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness

**Benefits:**

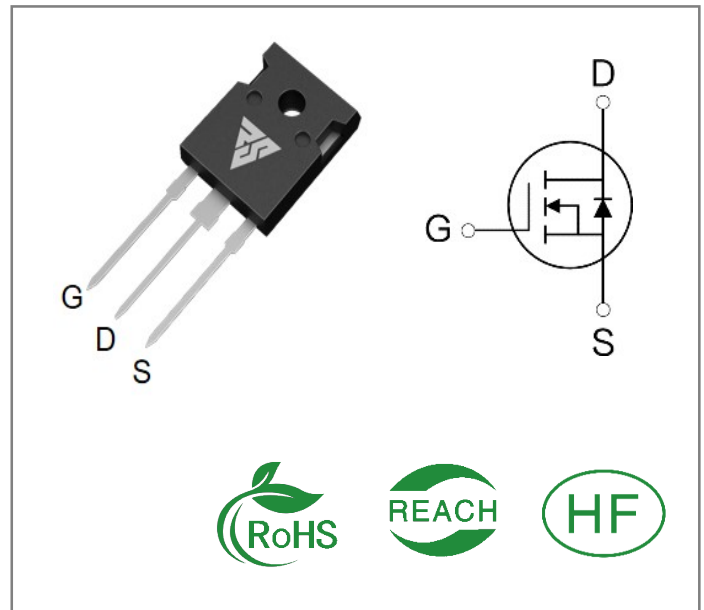
- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

**Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RSM120160W	TO-247-3	RSM120160W	Tube	30 PCS

**Maximum Ratings** (TJ= 25℃ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
VDSmax	Drain - Source Voltage	1200	V	VGS=0V, ID =100μA	
VGSmax	Gate - Source Voltage	-8/+22	V	Absolute maximum values	
VGSop	Gate - Source Voltage	-4/+18	V	Recommended operational values	
ID	Continuous Drain Current	17 12	A	VGS=18V, TC =25℃ VGS=18V, TC =100℃	
ID(pulse)	Pulsed Drain Current	39	A	Pulse width tp limited by TJmax	
PD	Power Dissipation	83	W	TC =25℃, TJ =175℃	
TL	Solder Temperature	260	℃		
TJ, Tstg	Operating Junction and Storage Temperature	-55 to +175	℃		



**Electrical Characteristics** (T<sub>J</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
V(BR)DSS	Drain-Source Breakdown Voltage	1200			V	V <sub>GS</sub> =0V, I <sub>D</sub> =100μA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.9	2.6	4.0	V	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>DS</sub> =2.5mA, T <sub>C</sub> =25°C	
			1.8		V	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>DS</sub> =2.5mA, T <sub>C</sub> =175°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		1	100	μA	V <sub>DS</sub> = 1200V, V <sub>GS</sub> =0V	
I <sub>GSS</sub>	Gate-Source Leakage Current		10	250	nA	V <sub>GS</sub> =22V, V <sub>DS</sub> = 0V	
R <sub>DS(on)</sub>	Drain-Source on-state Resistance		140	185	mΩ	V <sub>GS</sub> =18V, I <sub>D</sub> =8.5A, T <sub>C</sub> =25°C	
			248	300	mΩ	V <sub>GS</sub> =18V, I <sub>D</sub> =8.5A, T <sub>C</sub> =175°C	
C <sub>iss</sub>	Input Capacitance		612		pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =1000 V, f=1MHz, V <sub>AC</sub> =25 mV	
C <sub>oss</sub>	Output Capacitance		34.5				
C <sub>rss</sub>	Reverse Transfer Capacitance		8.77				
E <sub>ON</sub>	Turn-On Switching Energy		305		μJ	V <sub>DS</sub> =800V, V <sub>GS</sub> =-4/18V, I <sub>D</sub> = 8.5A, R <sub>G(ext)</sub> = 2.5Ω, L= 100μH	
E <sub>OFF</sub>	Turn-Off Energy		48				
t <sub>d(on)</sub>	Turn-On Delay Time		7		ns	V <sub>DS</sub> =800V, V <sub>GS</sub> =-4/18 V I <sub>D</sub> = 8.5A, R <sub>G(ext)</sub> =2. 5 Ω , R <sub>L</sub> =20Ω	
t <sub>r</sub>	Rise Time		30				
t <sub>d(off)</sub>	Turn-Off Delay Time		16				
t <sub>f</sub>	Fall Time		22				
R <sub>G(int)</sub>	Internal Gate Resistance		5		Ω	f=1 MHz, V <sub>AC</sub> =25mV	
Q <sub>gs</sub>	Gate to Source Charge		7.8		nC	V <sub>DS</sub> =800V, V <sub>GS</sub> =-4/18V I <sub>D</sub> =8.5A	
Q <sub>gd</sub>	Gate to Drain Charge		12.1				
Q <sub>g</sub>	Total Gate Charge		42.5				

**Reverse Diode Characteristics** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Typ.	Max	Unit	Test Conditions	Note
VSD	Diode Forward Voltage	4.2		V	VGS=-4V, ISD =4.2A, T <sub>J</sub> = 25°C	
		3.9		V	VGS=-4V, ISD=4.2 A, T <sub>J</sub> = 175°C	
IS	Continuous Diode Forward Current		17	A	TC= 25°C	
trr	Reverse Recovery time	20		ns	ISD= 8.5 A, VR = 800V	
Qrr	Reverse Recovery Charge	29		nC		
Irrm	Peak Reverse Recovery Current	2.5		A		

**Thermal Characteristics** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
R <sub>θJC</sub>	Thermal Resistance from Junction to Case	1.75	°C/W		
R <sub>θJA</sub>	Thermal Resistance From Junction to Ambient	40			

## Typical Feature Curve

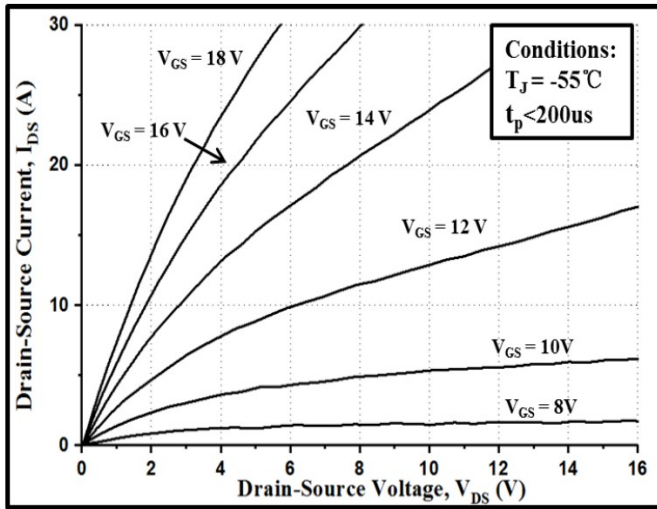


Figure 1. Output Characteristics  $T_j = -55^\circ\text{C}$

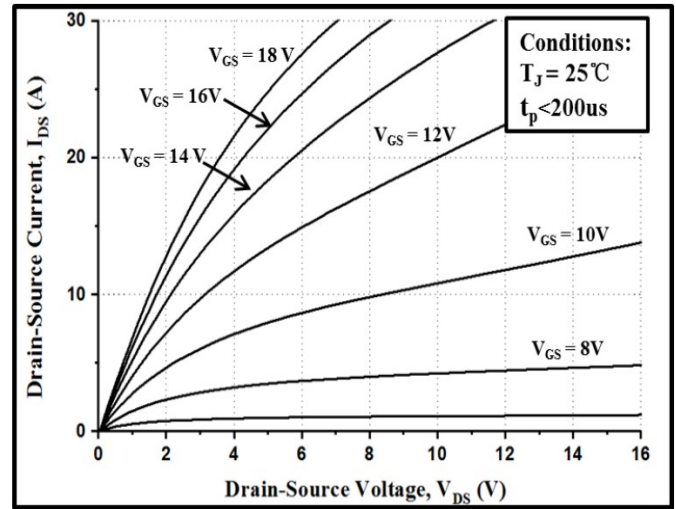


Figure 2. Output Characteristics  $T_j = 25^\circ\text{C}$

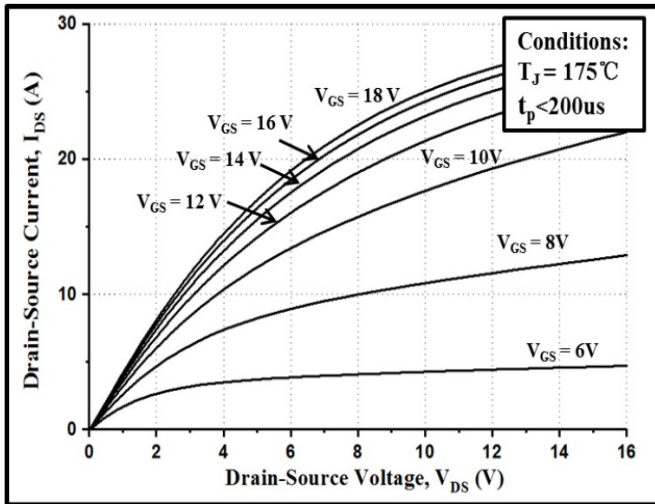


Figure 3. Output Characteristics  $T_j = 175^\circ\text{C}$

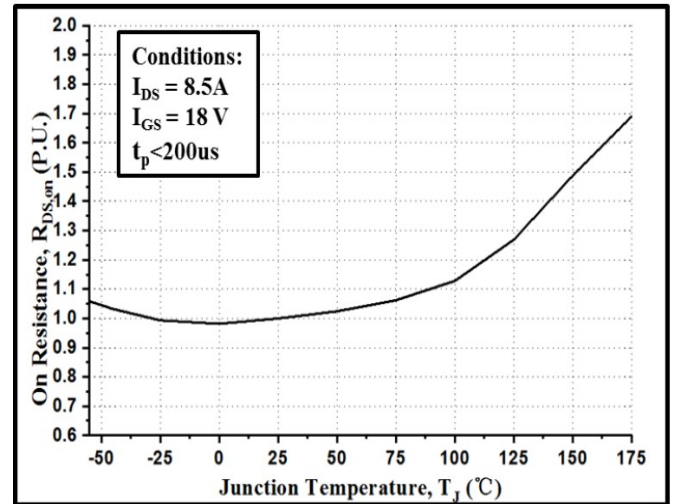


Figure 4. Normalized On-Resistance vs. Temperature

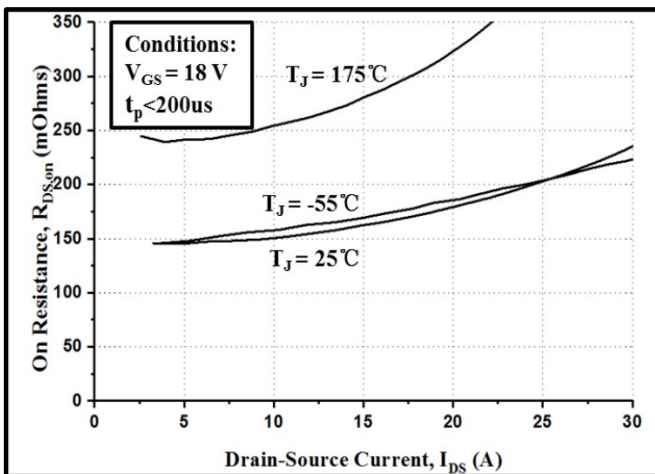


Figure 5. On-Resistance vs. Drain Current  
For Various Temperatures

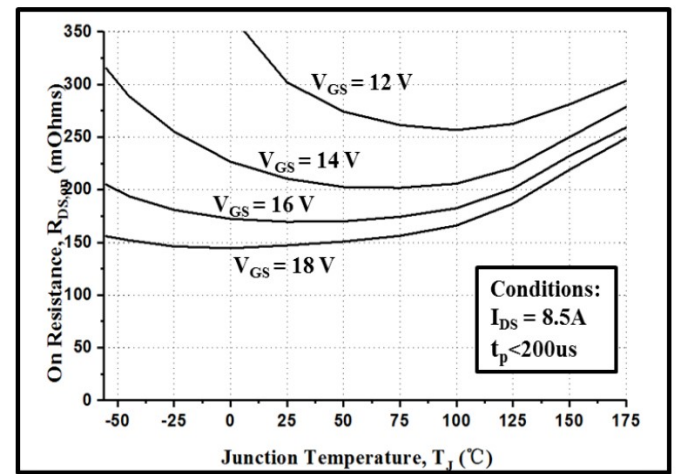


Figure 6. On-Resistance vs. Temperature  
For Various Gate Voltage



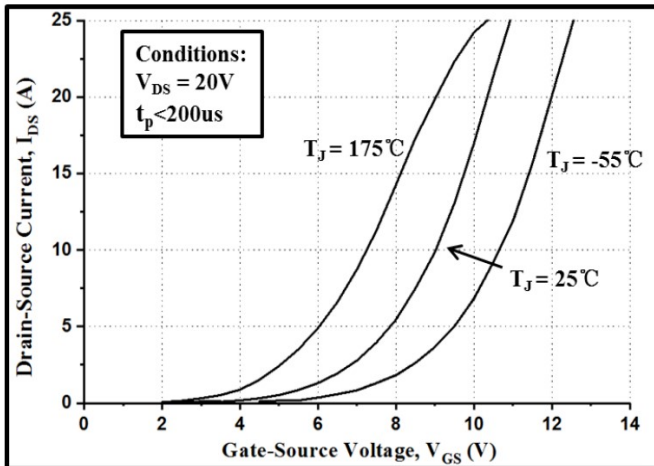


Figure 7. Transfer Characteristic for Various Junction Temperatures

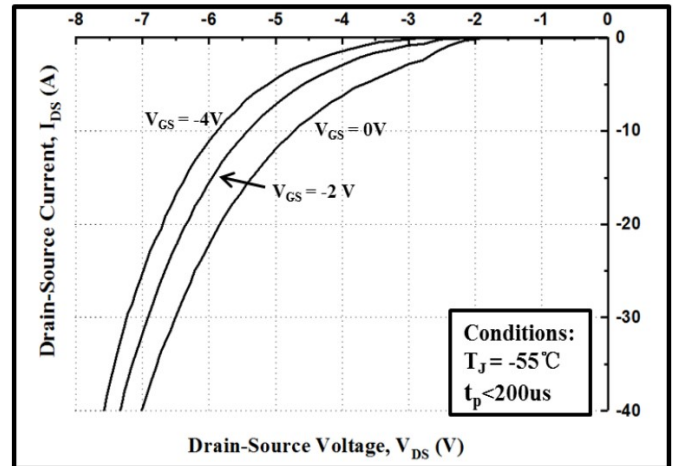


Figure 8. Body Diode Characteristic at -55°C

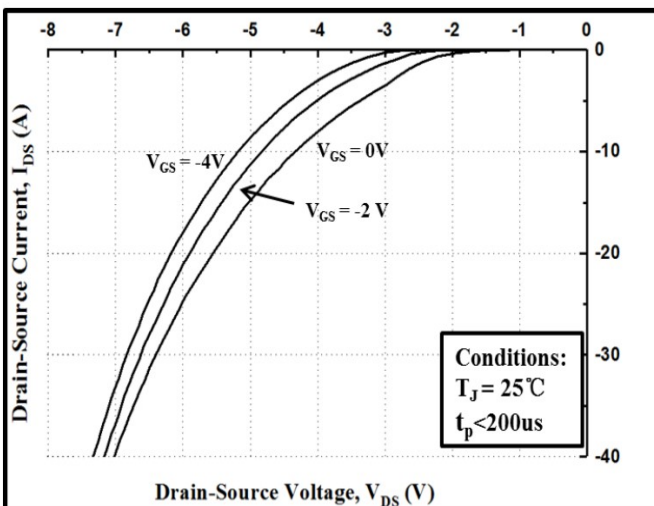


Figure 9. Body Diode Characteristic at 25°C

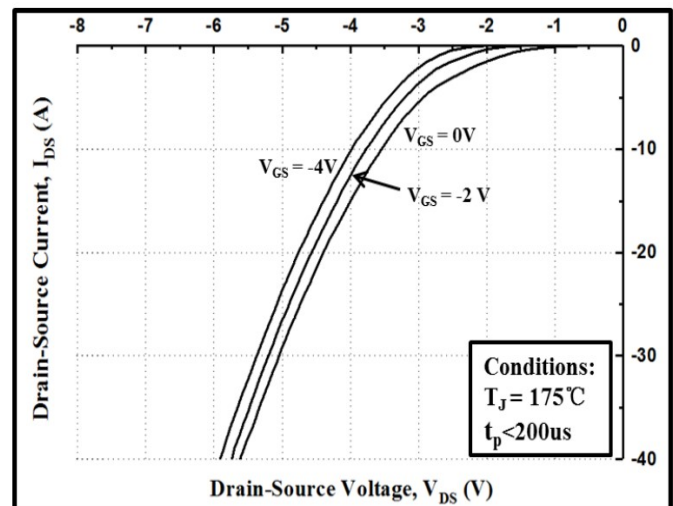


Figure 10. Body Diode Characteristic at 175°C

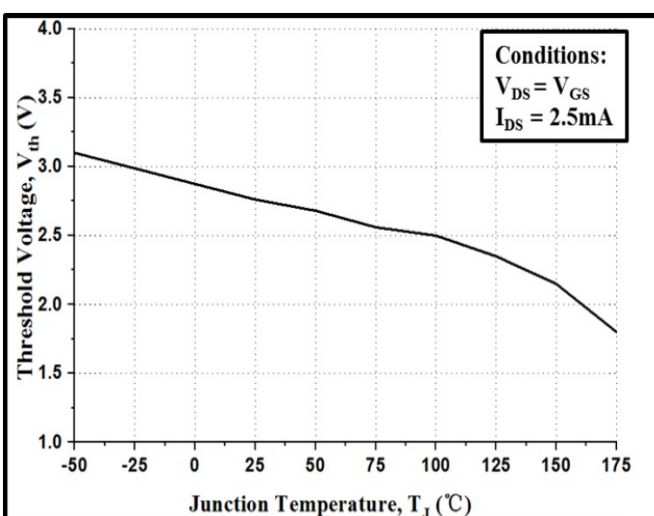


Figure 11. Threshold Voltage vs. Temperature

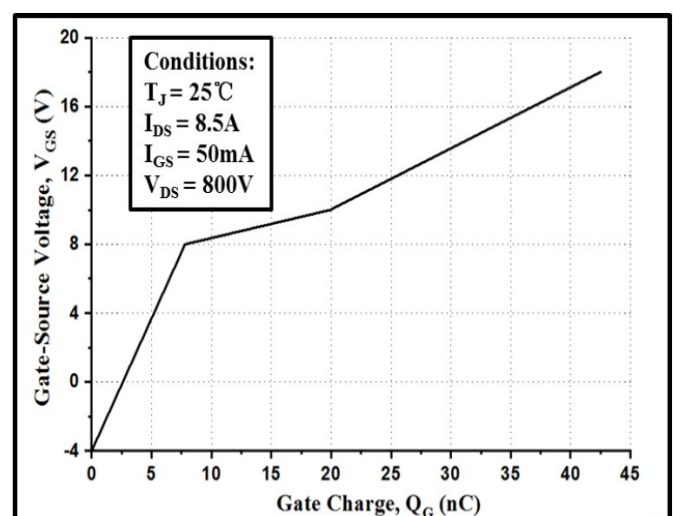


Figure 12. Gate Charge Characteristics

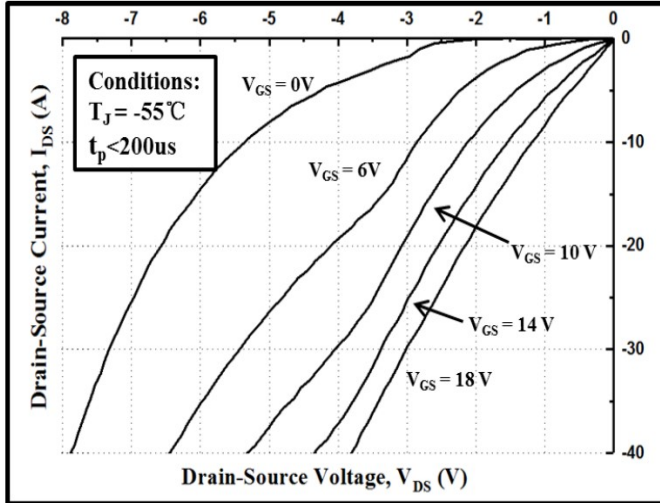


Figure 13. 3rd Quadrant Characteristic at -55°C

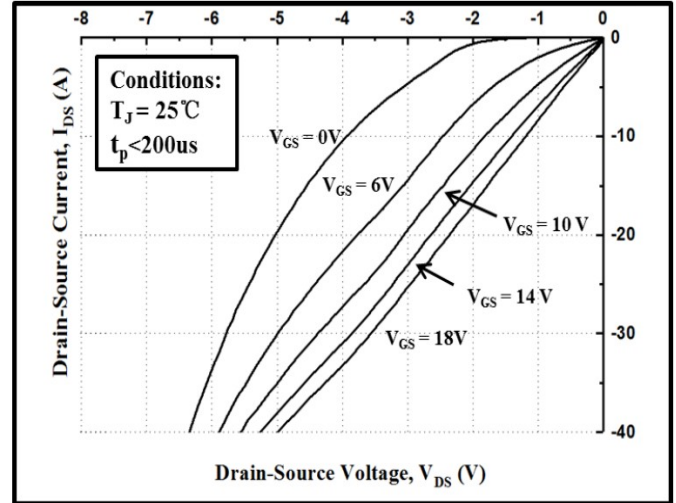


Figure 14. 3rd Quadrant Characteristic at 25°C

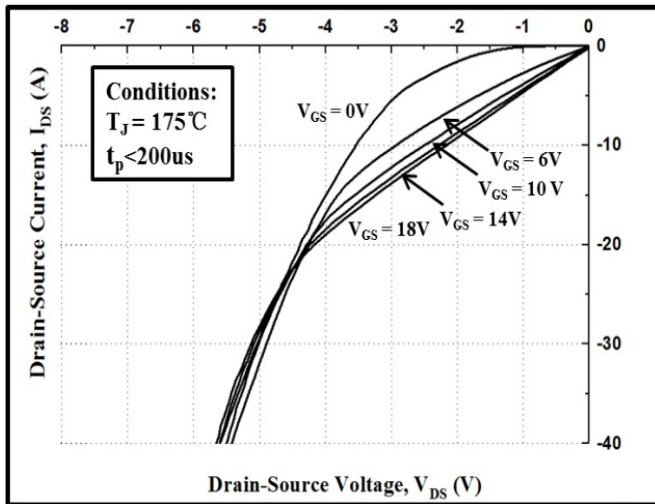


Figure 15. 3rd Quadrant Characteristic at 175 °C

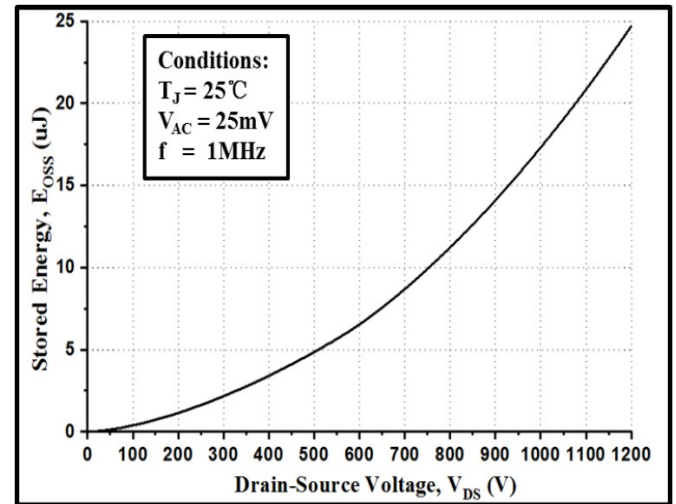


Figure16. Output Capacitor Stored Energy

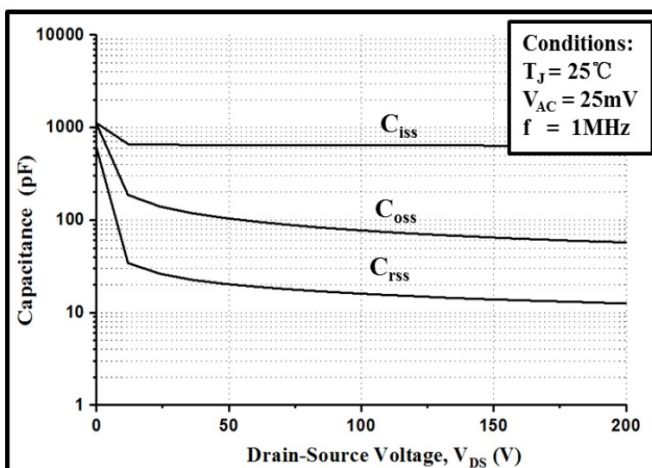


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

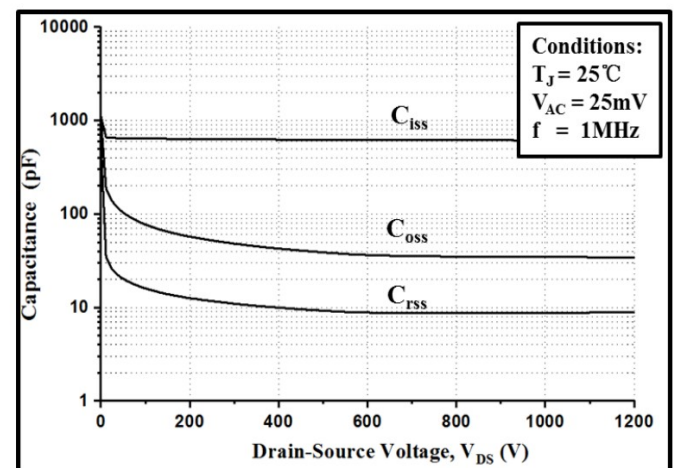


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1200V)

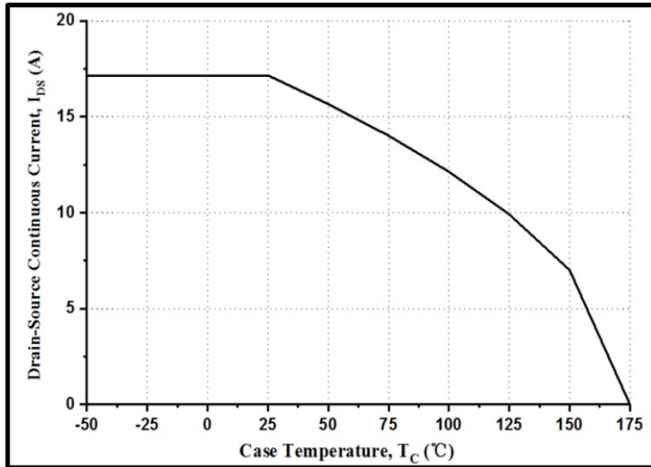


Figure 19. Continuous Drain Current Derating vs. Case Temperature

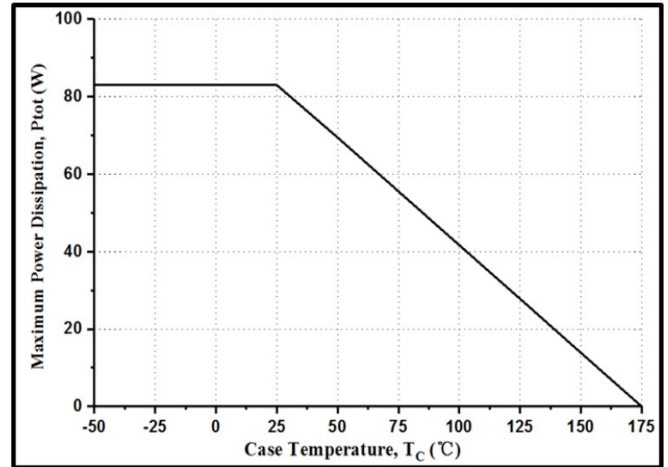


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

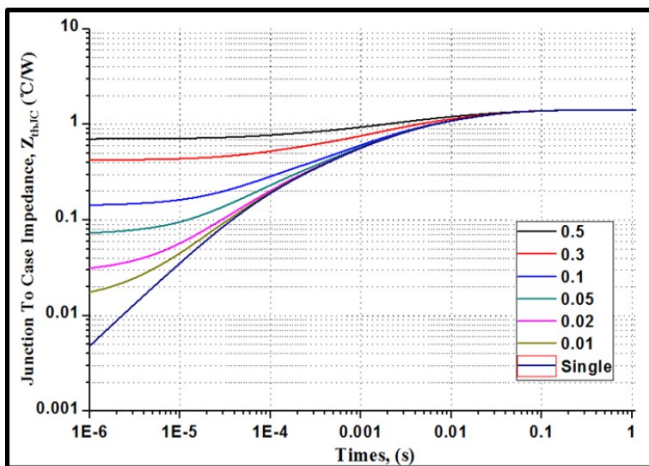


Figure 21. Transient Thermal Impedance (Junction - Case)

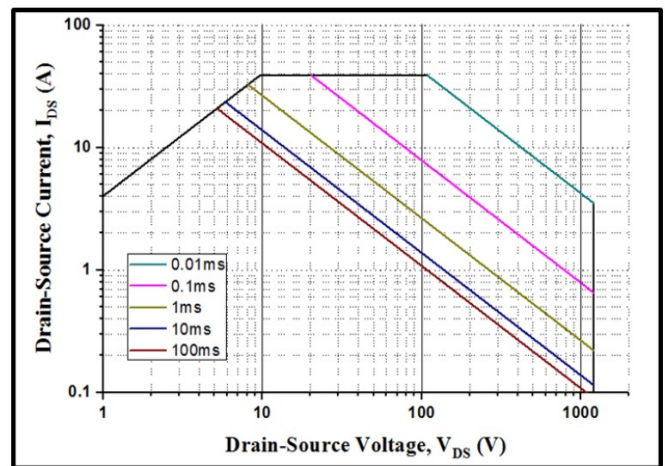


Figure 22. Safe Operating Area

## Test Circuit Schematic

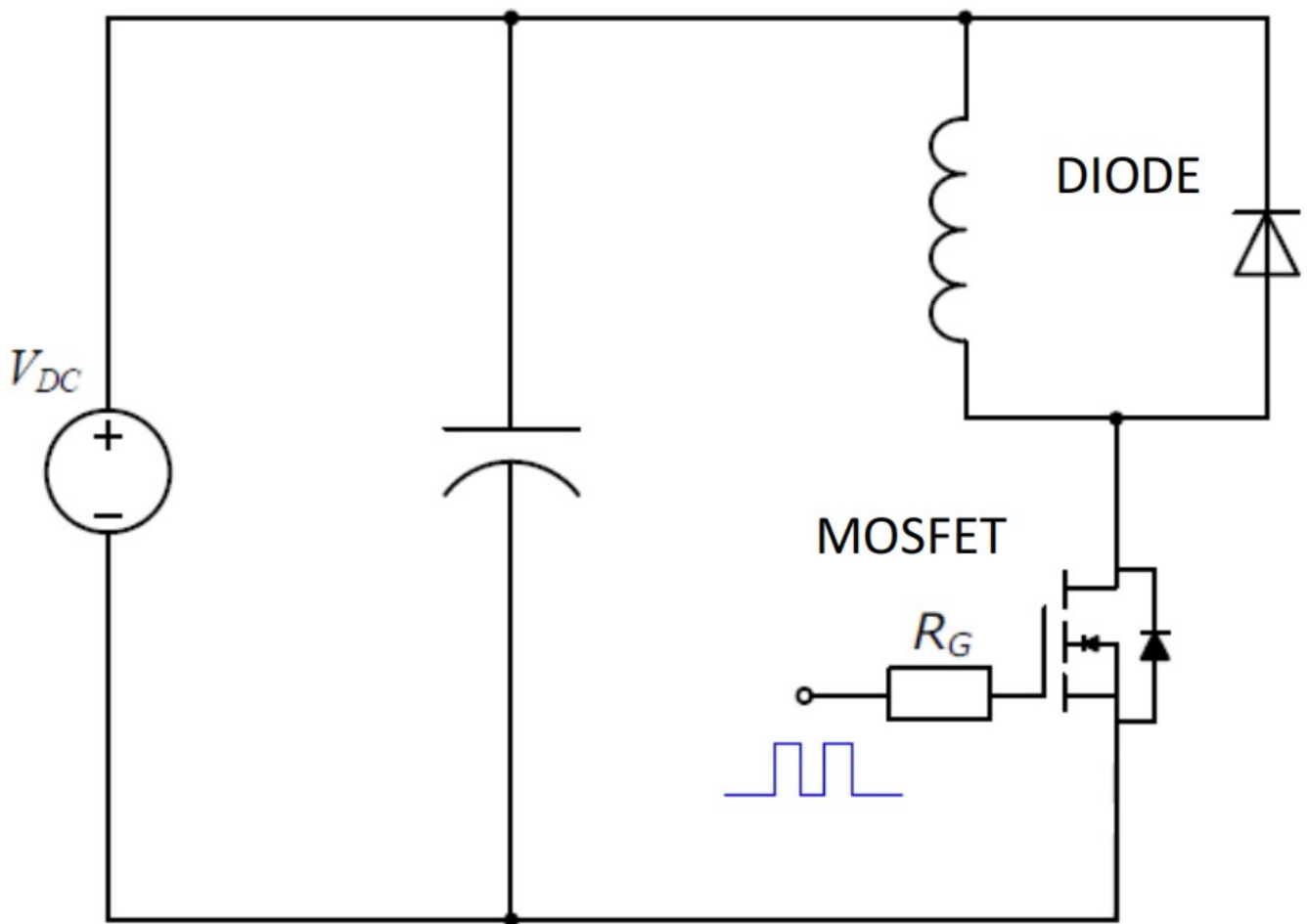
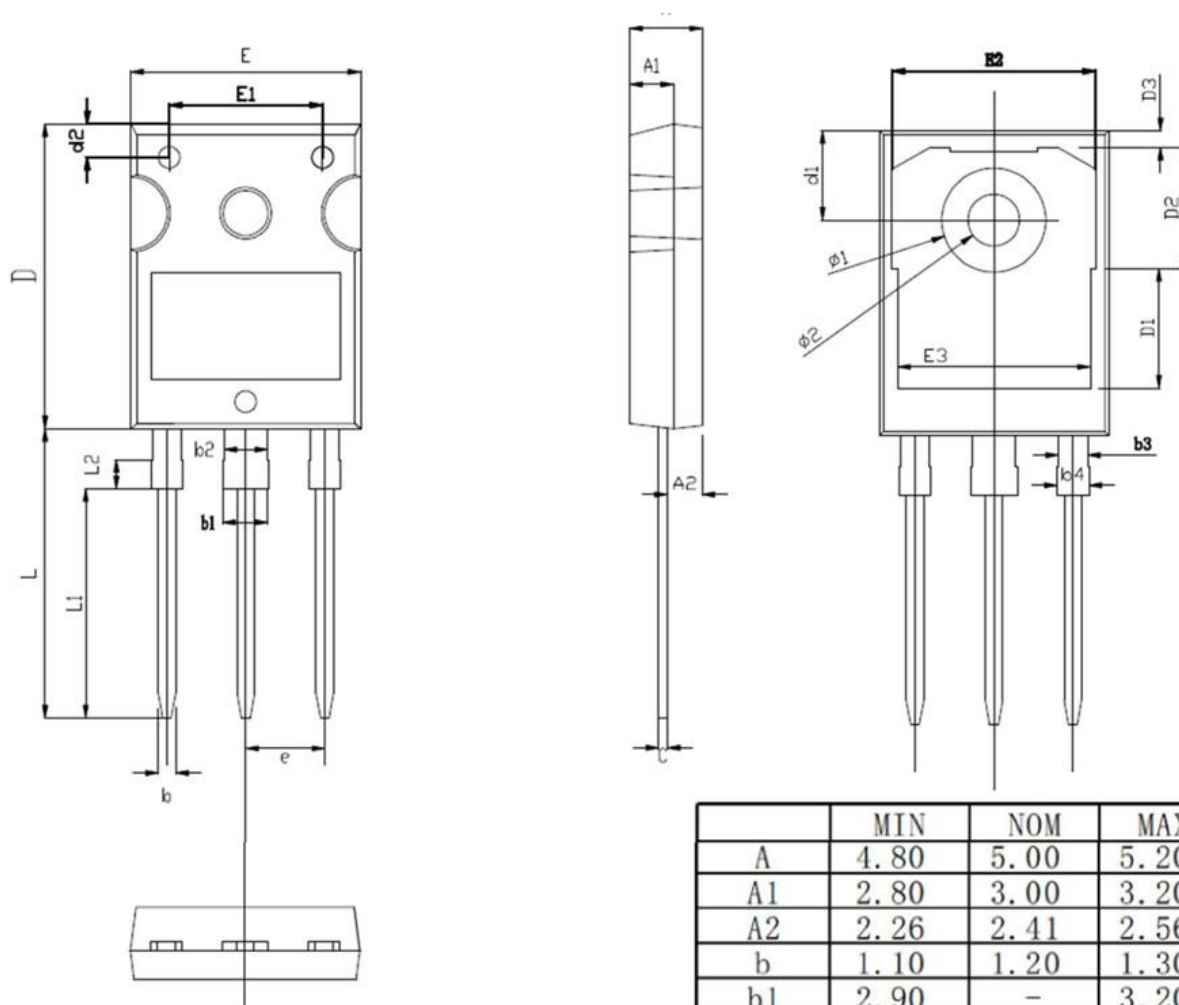


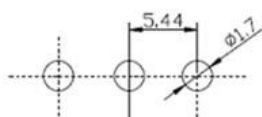
Figure 23. Clamped Inductive Switching  
Waveform Test Circuit



Package outline drawing(TO-247-3 Unit: mm )



RECOMMENDED LAND PATTERN



UNIT: mm

	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.80	3.00	3.20
A2	2.26	2.41	2.56
b	1.10	1.20	1.30
b1	2.90	-	3.20
b2	2.90	3.00	3.10
b3	1.90	2.00	2.10
b4	2.00	-	2.20
c	0.50	0.60	0.70
D	20.80	21.00	21.20
D1		8.23	
D2		8.32	
D3		1.17	
d1	6.00	6.15	6.30
d2	2.20	2.30	2.40
E	15.60	15.80	16.00
E1		10.50	
E2		14.02	
E3		13.50	
e	5.34	5.44	5.54
L	19.72	19.92	20.12
L1		15.79	
L2		1.98	
ø1	7.10	7.19	7.30
ø2	3.50	3.60	3.70

**Disclaimers:**

Reasunos Semiconductor Technology Co.Ltd (Reasunos) reserves the right to make changes without notice in order to improve reliability,function or design and to discontinue any product or service without notice .Customers should obtain the latest relevant information before orders and should verify that such information in current and complete.All products are sold subject to Reasunos's terms and conditions supplied at the time of orderacknowledgement.

Reasunos Semiconductor Technology Co.Ltd warrants performance of its hardware products to the specifications at the time of sale.Testing,reliability and quality control are used to the extene Reasunos deems necessary to support this warrantee. Except where agreed upon by contr- actual agreement,testing of all parameters of each product is not necessarily performed.

Reasunos Semiconductor Technology Co.Ltd does not assume any liability arising from the use of any product or circuit designs described herein.Customers are responsible for their products and applications using Reasunos's components.To minimize risk,customers must provide adequate design and operating safeguards.

Reasunos Semiconductor Technology Co.Ltd does not warrant or convey any license eith- er expressed or implied under its patent rights,nor the rights of others.Reproduction of inform- ation in Reasunos's data sheets or data books is permissible only if reproduction is without modification oralteration.Reproduction of this information with any alteration is an unfair and deceptive business practice. Reasunos Semiconductor Technology Co.Ltd is not responsi- ble or liable for such altered documentation.

Resale of Reasunos's products with statements different from or beyond the parameters stated by Reasunos Semiconductor Technology Co.Ltd for that product or service voids all exp- ress or implied warranties for the associated Reasunos's product or service and is unfair and deceptive business practice. Reasunos Semiconductor Technology Co.Ltd is not responsi- ble or liable for such statements.

**Life Support Policy:**

Reasunos Semiconductor Technology Co.Ltd's Products are not authorized for use as cri- tical components in life support devices or systems without the expressed written approval of Reasunos Semiconductor Technology Co.Ltd.

As used herein:

1. Life support devices or systems are devices or systems which: a.are intended for surgical implant into the human body, b.support or sustain life, c.whose failuer to when properly used in accordance with instructions for used provided in the laeling,can be reasonably expected to result in significant injury to the user.

2.A critical component is any component of a life support device or system whose failure to system whose failure to perform can be reasonably expected to cause the failure of the life support device or system,or to affect its safety or effectiveness.